

Product Change Notice (PCN)

Subject: ISL94212 Design Change

Publication Date: 3/27/2015

Effective Date: 6/26/2015

Revision Description:

Initial Release

Description of Change:

This notice is to advise our customers of a minor silicon design revision.

Reason for Change:

Intersil has identified a low PPM EEPROM checksum issue that results in the EEPROM not reading correctly. Intersil has a test screen that eliminates the majority of these failures (at ambient), but cannot guarantee a 100% test screen below -20°C. To resolve the EEPROM issue, Intersil has validated a solution to the problem with a metal edit to the silicon. The silicon metal edit changes the initial value of the internal V3P3 power supply from 3.35V to 3.55V during an EEPROM load event. The change in supply voltage to the EEPROM provides additional voltage supply headroom for each NMOS device in series with each memory cell. The desired V3P3 supply voltage that is loaded after the EEPROM read operation then returns to 3.35V, identical to current device operation / specification.

Impact on fit, form, function, quality & reliability:

The change will have no impact on the form, fit, function, quality, reliability and environmental compliance of the devices.

Product Identification:

There will be no change in the external marking of the packaged parts or to the product data sheet electrical specification. Product affected by this change is identifiable via Intersil's internal traceability system.

Qualification status: Complete

Sample availability: 3/27/2015

Device material declaration: Available upon request

Questions or requests pertaining to this change notice, including additional data or samples, must be sent to Intersil within 30 days of the publication date.

For additional information regarding this notice, please contact your regional change coordinator (below)			
Americas: PCN-US@INTERSIL.COM	Europe: PCN-EU@INTERSIL.COM	Japan: PCN-JP@INTERSIL.COM	Asia Pac: PCN-APAC@INTERSIL.COM

Appendix A - Affected Products List (see attached)

Appendix B - Qualification Results (see attached)

Appendix A:

ISL94212ANZ ISL94212ANZ-T ISL94212INZ ISL94212INZ-T ISL94212INZ-TR5564

Appendix B:

Stress	Sample Size	# of Lots	Result	Comments
Temperature Cycling (JESD22-A104)	240	3	Pass	500 cycles, -50°C to 150°C
Temperature Characterization	30	1	Pass	Evaluated at 25, -40, and 105°C
Human Body Model (JESD22-A114))	3	1	Pass	2000 v
Charged Device Model (JESD22-C101)	3	1	Pass	1000 v